	Search Notes							

Application/Control No.	Applicant(s)/Patent under Reexamination	
10/629,634	IWAI ET AL.	
Examiner	Art Unit	
TUAN A PHAM	2618	

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Class	Subclass	Date	Examiner
455	575.1	7/10/2007	PHAM
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	575.7	7/10/2007	РНАМ
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INT	INTERFERENCE SEARCHED				
Class	Subclass	Date	Examiner		

SEARC (INCLUDING SE	H NOTES ARCH STRATEG	Y)
	DATE	EXMR
Consulted with:		
Duc Nguyen	9/1/2006	PHAM